

# STDFv3-Specific Records

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## Site-Specific Hardware Bin Record (SHB)

### Function

Stores a count of the parts tested at one test site that are physically placed in a particular bin after testing.

The SHB stores site-specific information, that is, information generated at one site of the tester. It is therefore a subset of the Hardware Bin Record (HBR), which collects information from all the sites of a tester.

The STDF specification also supports a Site-specific Software Bin Record (SSB), for logical binning categories. The part is actually placed in a hardware bin after testing. A part can be logically associated with a software bin during or after testing.

### Data Fields

Field Name	Data Type	Field Description	Missing/Invalid Data Flag
REC_LEN	U*2	Bytes of data following header	
REC_TYP	U*1	Record type (25)	
REC_SUB	U*1	Record sub-type (10)	
HEAD_NUM	U*1	Test head number	
SITE_NUM	U*1	Test site number	
HBIN_NUM	U*2	Hardware bin number	
HBIN_CNT	U*4	Number of parts in bin	
HBIN_NAM	C*n	Name of hardware bin	length byte = 0

### Notes on Specific Fields

**HBIN\_NUM** Has legal values in the range 0 to 32767.

### Possible Use

Site-specific Summary Sheet

### Frequency

For each site summarized, one per hardware bin used.

May be included to name unused bins.

### Location

Anywhere in the data stream after the MIR.

When data is being recorded in real time, this record usually appears near the end of the data stream.

## Site-Specific Software Bin Record (SSB)

### Function

Stores a count of the parts tested at one test site that are associated with a particular logical bin after testing.

The SSB stores site-specific information, that is, information generated at one site of the tester. It is therefore a subset of the Software Bin Record (SBR), which collects information from all the sites of a tester.

The STDF specification also supports a Site-specific Hardware Bin Record (SHB), for physical binning categories. The part is actually placed in a hardware bin after testing. A part can be logically associated with a software bin during or after testing.

### Data Fields

Field Name	Data Type	Field Description	Missing/Invalid Data Flag
REC_LEN	U*2	Bytes of data following header	
REC_TYP	U*1	Record type (25)	
REC_SUB	U*1	Record sub-type (20)	
HEAD_NUM	U*1	Test head number	
SITE_NUM	U*1	Test site number	
SBIN_NUM	U*2	Software bin number	
SBIN_CNT	U*4	Number of parts in bin	
SBIN_NAM	C*n	Name of software bin	length byte = 0

### Notes on Specific Fields

SBIN\_NUM Has legal values in the range 0 to 32767.

### Possible Use

Site-specific Summary Sheet

### Frequency

For each site summarized, one per software bin used.

May be included to name unused bins.

### Location

Anywhere in the data stream after the MIR.

When data is being recorded in real time, this record usually appears near the end of the data stream.

## Site-Specific Test Synopsis Record (STS)

### Function

Contains the test execution and failure counts at one test site for one parametric or functional test in the test plan. The STS stores site-specific information, that is, information generated at one site of the tester. It is therefore a subset of the Test Synopsis Record (TSR), which collects information from all the sites of a tester.

### Data Fields

Field Name	Data Type	Field Description	Missing/Invalid Data Flag
REC_LEN	U*2	Bytes of data following header	
REC_TYP	U*1	Record type (25)	
REC_SUB	U*1	Record sub-type (30)	
HEAD_NUM	U*1	Test head number	
SITE_NUM	U*1	Test site number	
TEST_NUM	U*4	Test number	
EXEC_CNT	I*4	Number of test executions	-1
FAIL_CNT	I*4	Number of test failures	-1
ALRM_CNT	I*4	Number of alarmed tests	-1
OPT_FLAG	B*1	Optional Data Flag	See note
PAD_BYTE	B*1	Reserved for future use	See note
TEST_MIN	R*4	Lowest test result value	OPT_FLAG bit 0 = 1
TEST_MAX	R*4	Highest test result value	OPT_FLAG bit 1 = 1
TST_MEAN	R*4	Mean of test result values	OPT_FLAG bit 2 = 1
TST_SDEV	R*4	Standard Deviation of test values	OPT_FLAG bit 3 = 1
TST_SUMS	R*4	Sum of test result values	OPT_FLAG bit 4 = 1
TST_SQRS	R*4	Sum of Squares of test result values	OPT_FLAG bit 5 = 1
TEST_NAM	C*n	Test Name length	length byte = 0
SEQ_NAME	C*n	Sequencer (program segment) name	length byte = 0
TEST_LBL	C*n	Test text or label	length byte = 0

## Notes on Specific Fields

<b>EXEC_CNT,</b> <b>FAIL_CNT,</b> <b>ALRM_CNT</b>	Are optional, but are strongly recommended because they are needed to compute values for complete site summary sheets. (The value -1 marks each field as invalid.)
<b>OPT_FLAG</b>	Is the Optional Data Flag, and contains the following bits:  bit 0 set = <b>TEST_MIN</b> data is invalid bit 1 set = <b>TEST_MAX</b> data is invalid bit 2 set = <b>TST_MEAN</b> data is invalid bit 3 set = <b>TST_SDEV</b> data is invalid bit 4 set = <b>TST_SUMS</b> data is invalid bit 5 set = <b>TST_SQRS</b> data is invalid Bits 6 - 7 are reserved for future use and must be 0
<b>PAD_BYTE</b>	Causes alignment of the following fields. It is reserved for future use and must be 0.
<b>OPT_FLAG,</b> <b>PAD_BYTE</b>	Are optional only by leaving them off the end of the record. If any of the following fields exists, they must also be present.
<b>TST_MEAN,</b> <b>TST_SDEV</b>	Are the test mean and standard deviation, and are calculated after excluding alarmed tests.
<b>TST_SUMS,</b> <b>TST_SQRS</b>	Are useful in calculating the mean and standard deviation when combining test data from multiple lots.
<b>TEST_NAM,</b> <b>SEQ_NAME</b>	Are the test name and sequencer name, and should be included, if they exist, so that they can be printed on site-specific summary sheets using this record.

## Possible Use

Site-specific Summary Sheet

## Frequency

For each site summarized, one for each test executed in the test plan.

## Location

Anywhere in the data stream after the corresponding PDR or FDR (if one exists).

Usually occurs after the last datalogged result for that test if datalogging is enabled.

## Site-Specific Part Count Record (SCR)

### Function

Contains part count totals for parts tested at a single test site.

The SCR stores site-specific information, that is, information generated at one site of the tester. It is therefore a subset of the Master Results Record (MRR), which collects information from all the sites of a tester.

### Data Fields

Field Name	Data Type	Field Description	Missing/Invalid Data Flag
REC_LEN	U*2	Bytes of data following header	
REC_TYP	U*1	Record type (25)	
REC_SUB	U*1	Record sub-type (40)	
HEAD_NUM	U*1	Test head number	
SITE_NUM	U*1	Test site number	
FINISH_T	U*4	Date/time last part tested at site	binary 0
PART_CNT	U*4	Number of parts tested	
RTST_CNT	I*4	Number of parts retested	-1
ABRT_CNT	I*4	Number of aborts during testing	-1
GOOD_CNT	I*4	Number of good (passed) parts tested	-1
FUNC_CNT	I*4	Number of functional parts tested	-1

### Possible Use

Site-specific Summary Sheet

### Frequency

One for each test site summarized.

### Location

May be located anywhere between the MIR and MRR.

This record will usually be found near the end of the file after all parts have been tested.